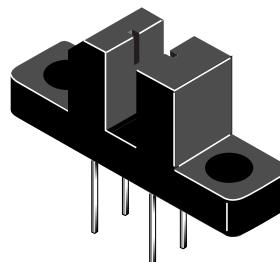
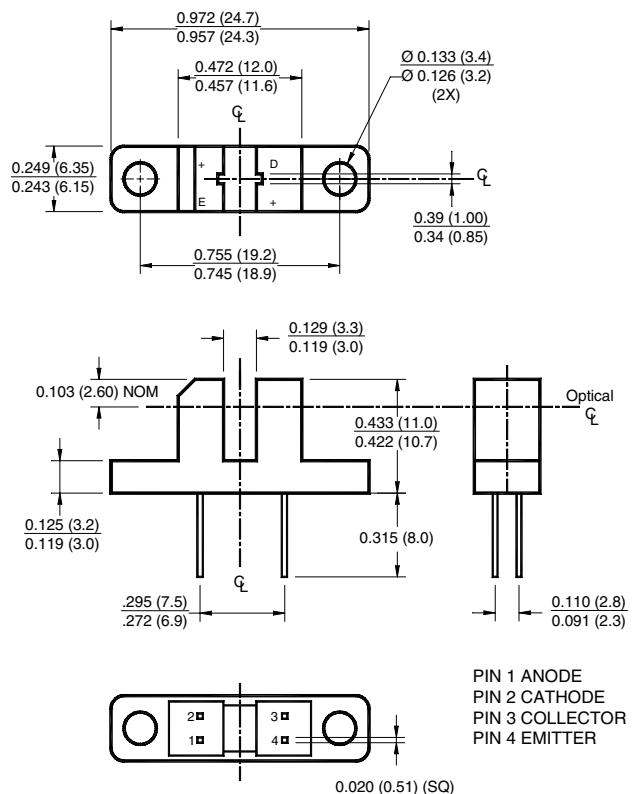
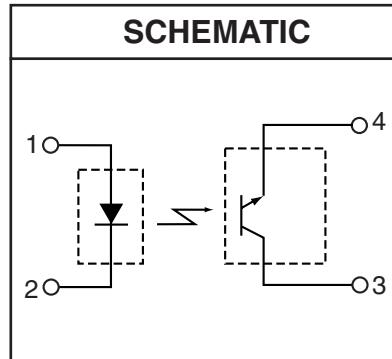


**PACKAGE DIMENSIONS**



**NOTES:**

1. Dimensions for all drawings are in inches (mm).
2. Tolerance of  $\pm .010$  (.25) on all non-nominal dimensions unless otherwise specified.



**DESCRIPTION**

The CNY28 is a gallium arsenide infrared emitting diode coupled with a silicon phototransistor in a plastic housing. The gap in the housing provides a means of interrupting the signal with tape, cards, shaft encoders or other opaque material, switching the output from an "ON" to an "OFF" state.

**FEATURES**

- Opaque housing
- Low cost
- 0.035" apertures
- European "Pro Electron" registered

**ABSOLUTE MAXIMUM RATINGS** ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Rating	Units
Operating Temperature	$T_{OPR}$	-55 to +85	°C
Storage Temperature	$T_{STG}$	-55 to +85	°C
Soldering Temperature (Iron) <sup>(2,3,4)</sup>	$T_{SOL-I}$	240 for 5 sec	°C
Soldering Temperature (Flow) <sup>(2,3)</sup>	$T_{SOL-F}$	260 for 10 sec	°C
<b>INPUT (EMITTER)</b>			
Continuous Forward Current	$I_F$	50	mA
Reverse Voltage	$V_R$	6	V
Power Dissipation <sup>(1)</sup>	$P_D$	100	mW
<b>OUTPUT (SENSOR)</b>			
Collector-Emitter Voltage	$V_{CEO}$	30	V
Emitter- Collector Voltage	$V_{ECO}$	4.5	V
Collector Current	$I_C$	20	mA
Power Dissipation <sup>(1)</sup>	$P_D$	150	mW

NOTES:

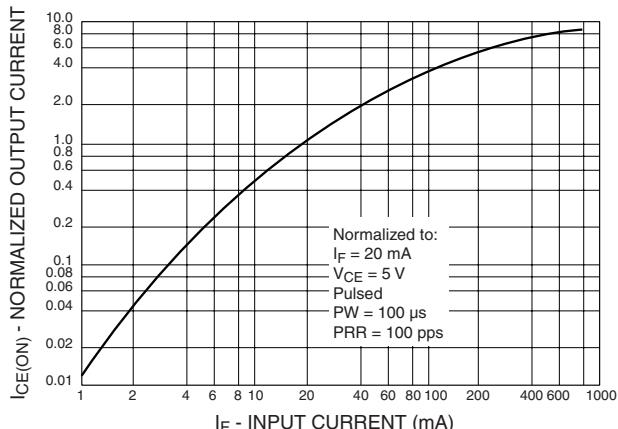
- Derate power dissipation linearly 1.67 mW/°C above 25°C.
- RMA flux is recommended.
- Methanol or isopropyl alcohols are recommended as cleaning agents.
- Soldering iron 1/16" (1.6mm) from housing.

**ELECTRICAL / OPTICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$ )

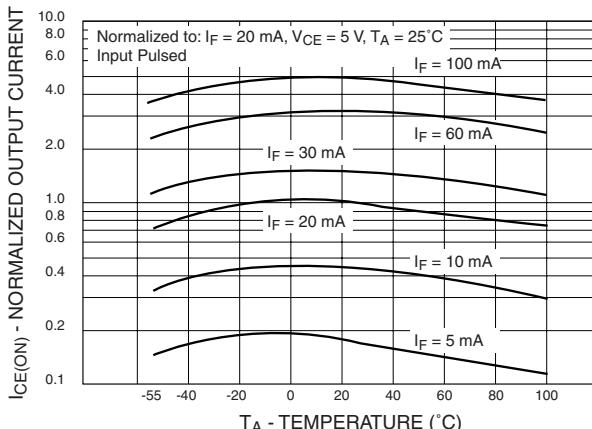
PARAMETER	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNITS
<b>INPUT (EMITTER)</b>						
Forward Voltage	$I_F = 10 \text{ mA}$	$V_F$	—	—	1.7	V
Reverse Leakage Current	$V_R = 2 \text{ V}$	$I_R$	—	—	10	μA
<b>OUTPUT (SENSOR)</b>						
Emitter-Collector Breakdown	$I_E = 100 \mu\text{A}, E_e = 0$	$BV_{ECO}$	5.0	—	—	V
Collector-Emitter Breakdown	$I_C = 10 \text{ mA}, E_e = 0$	$BV_{CEO}$	30	—	—	V
Collector-Emitter Leakage	$V_{CE} = 10 \text{ V}, E_e = 0$	$I_{CEO}$	—	—	100	nA
<b>COUPLED</b>						
Collector Current	$I_F = 20 \text{ mA}, V_{CE} = 10 \text{ V}$	$I_{C(ON)}$	0.20	—	—	mA
Collector Emitter Saturation Voltage	$I_F = 20 \text{ mA}, I_C = 25 \mu\text{A}$	$V_{CE(SAT)}$	—	—	0.40	V
Turn-On Time	$I_F = 30 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 2.5 \text{ k}\Omega$	$t_{on}$	—	5	—	μs
Turn-Off Time	$I_F = 30 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 2.5 \text{ k}\Omega$	$t_{off}$	—	5	—	μs

**TYPICAL PERFORMANCE CURVES**

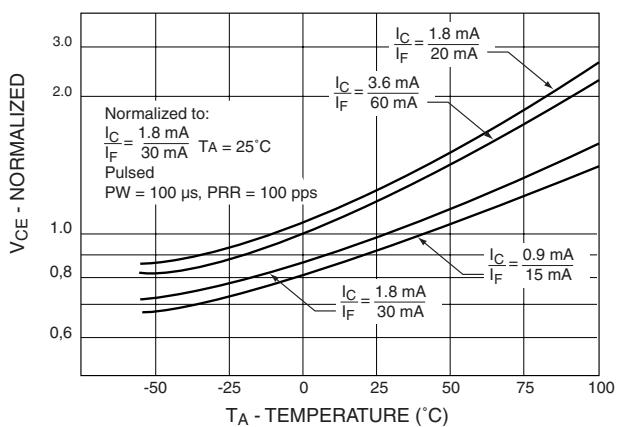
**Fig. 1 Output Current vs. Input Current**



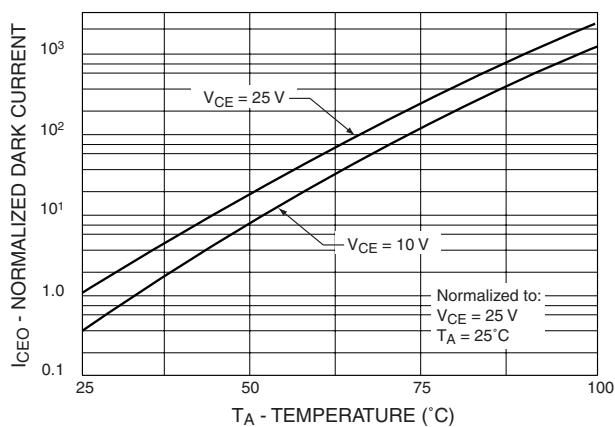
**Fig. 2 Output Current vs. Temperature**



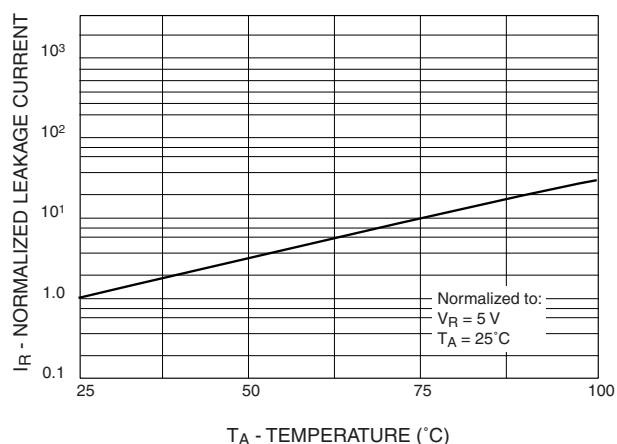
**Fig. 3 Saturation Voltage vs. Ambient Temperature**



**Fig. 4 Normalized Dark Current  
vs. Ambient Temperature (Detector)**

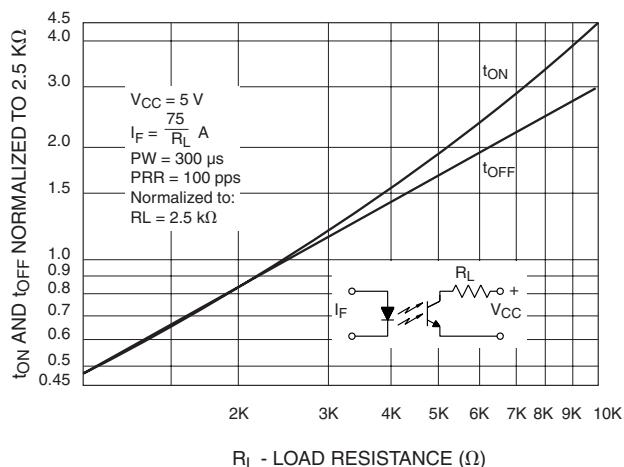


**Fig. 5 Normalized Leakage Current  
vs. Ambient Temperature (Emitter)**

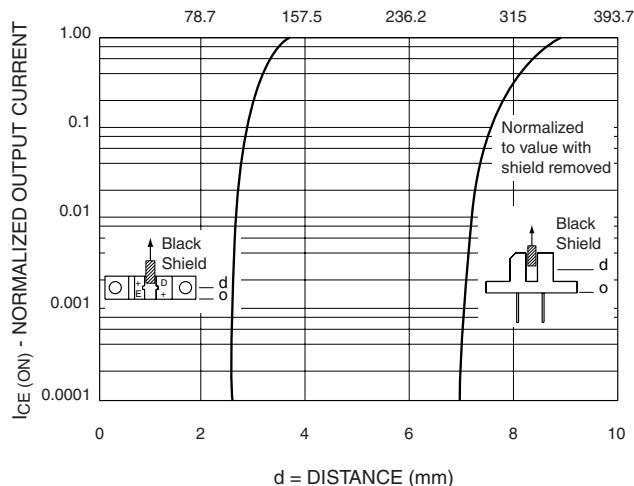


**TYPICAL PERFORMANCE CURVES**

**Fig. 6 Switching Time vs. Load Resistance**



**Fig. 7 Output Current vs. Distance**



**DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

**LIFE SUPPORT POLICY**

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in labeling, can be reasonably expected to result in a significant injury of the user.
2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.